Application/Control No.	Applicant(s)/Patent under Reexamination		
10/081,476	NIVEN ET AL.		
Examiner	Art Unit		
Jungwon Chang	2154		

SEARCHED					
Class	Subclass	Date	Examiner		
463	39 9 40 42	5/13/2005	JWC		
455	552.1	5/13/2005	JMC		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	 				
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
East text search NPL: Google ACM IEEE search report attached	5/13/2005	JWC
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